Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/774,656	DUONG, CHAU H.
Examiner	Art Unit

1765

Kin-Chan Chen

SEARCHED						
Class	Subclass	Date	Examiner			
252	79. 1	19/4/05	kcc			
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451	41					
451	259					
438	691					
48	693	10/4/5	kci			

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
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